

CONFERENCE FEE

Conference Fee includes: participation in all sessions, CAS Welcome Cocktail, Banquet and lunches as well as the CAS 2009 Proceedings.

The payment for the Conference Fee will be made in EUR or equivalent RON.

Cheques are not accepted.

Conference Fee	Before September 15 th	After September 15 th
IEEE Non-Member	350 EUR	400 EUR
IEEE Member	300 EUR	350 EUR
Students	180 EUR	200 EUR

Participants will send the Conference Fee by bank transfer (**bank commission not included**) to the **IMT-Bucharest** account, open for CAS 2009:

Account:

IBAN RO 20 BACX 000003001615002 (EUR)

SWFT: BACROBU

UNICREDIT TIRIAC BANK,

Marasesti Branch,

Splaiul Unirii, No. 16, Sector 4,

040035 Bucharest, Romania

Ref. "Conference Fee-CAS 2009"

The Romanian participants will pay the Conference Fee by bank transfer (bank commission not included) to the **IMT-Bucharest Account IBAN RO 47 BACX 000003001615001 (Lei), SWFT: BACROBU, open for CAS 2009 at the Unicredit Tiriac Bank**(see the above mentioned address) or directly to: IMT-Bucharest, 32 B, Erou Iancu Nicolae Str., Bucharest, Romania.

CANCELLATION POLICY:

Participants are encouraged to register in advance for their own convenience. Due to printing and hotel commitments, refunds requested after September 15th cannot be guaranteed. A processing fee of 100 EUR or equivalent RON will be withheld from all refunds.

ORGANIZING COMMITTEE

General Chairman:

Dan Dascalu IMT-Bucharest

Technical Program Chair:

Adrian Rusu "Politehnica" University, Bucharest

Technical Program Vice Chair:

Irina Kleps IMT-Bucharest

Gheorghe Brezeanu "Politehnica" University, Bucharest

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CAS OFFICE ADDRESS

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<http://www.imt.ro/CAS>

CALL FOR PAPERS



INTERNATIONAL SEMICONDUCTOR CONFERENCE

MICRO- AND NANOTECHNOLOGIES

32nd Edition
October 12-14, 2009
Sinaia, Romania



organized by

National Institute for Research and
Development in Microtechnologies
(IMT-Bucharest)

co-sponsored by

IEEE - Electron Devices Society
Ministry for Education, Research and Innovation
IEEE - Romania Section
Electron Devices Chapter

under the aegis of
Romanian Academy
Electrochemical Society Inc.



SCOPE

The 2009 International Semiconductor Conference (CAS 2009) - former Annual Semiconductor Conference - is the 32nd of an annual sequence and is the 19th edition with international participation.

The aim of the conference is two-fold. First, it provides a forum of debate on selected topics of scientific research and technological development. On the other hand, this is an occasion for refreshing a broad perspective of the participants through invited papers and tutorials.

The Conference is underlying the development in micro-and nanotechnologies, still maintaining the "traditional" connection with semiconductor electronics.

TOPICS

- ❖ **Simulation and fabrication of microstructures and microsystems:** surface and bulk micromachining, microengineering techniques, electro-opto-mechanical microsystems, microsensor and actuator integration, signal processing, computational intelligence and system interfacing, biosensors and microsystems for biomedical applications; optical, opto-electronic and photonic functional components, RF MEMS;
- ❖ **Science and technology of nanostructures and nanostructured materials:** composite nanoparticles and nanostructures with selective properties, nanostructures and nanostructured materials with special properties, nanotechnologies and nanostructures;
- ❖ **Semiconductor device physics and technology:** device modelling and simulation, silicon and compound semiconductor devices, heterostructures, advanced materials and processes, reliability and defect engineering;
- ❖ **Design and technology of microelectronic components:** microelectronic, microphotonic and microwave integrated subsystems, devices and modules for power control and conversion, specialized electronic circuits integrated in the microelectronic technology, testing and reliability.

HIGHLIGHTS:

- ❖ Nanoscience and nanoengineering;
- ❖ Microoptics and microphotonics;
- ❖ Micromachined devices and circuits for microwave and millimeter wave applications;
- ❖ Micro and nanotechnologies for transducers, interfaces and microsystems;
- ❖ Micro and nanotechnologies for biomedical and environmental applications;
- ❖ Novel materials and intelligent materials;
- ❖ Power devices and microelectronics (including CAD).

CAS 2009 PROCEEDINGS

The contributed and invited papers will be published in the CAS 2009 Proceedings (an IEEE publication), which will be delivered to the participants at the beginning of the conference. The authors of the accepted papers must sign (for printing the paper in the Proceedings) an IEEE Copyright Form.

The papers submitted to CAS must be original and previously unpublished. By the IEEE Copyright form, the authors will transfer the copyright to IEEE.

CAS 2009 PROGRAM

CAS 2009 program will consist in contributed (structured in oral or poster sessions) and invited papers. In oral sessions authors should use PowerPoint presentations. The presentation should not exceed 20 minutes (contributed papers), respectively 30-40 minutes (invited papers), discussion included. The recommended format for posters is A0. The organizers may deliver on demand the A0 size colour posters, for an additional charge. The interested participants should send the electronic file of the poster to the address: print@imt.ro

The program will include a Student Papers Session. The best paper will be awarded by EDS Chapter. To be eligible, the paper must be based on the student's own work and the authors should mention their option to be registered in this session.

PAPERS TO BE SUBMITTED

Contributed papers will be selected on the basis of a four pages paper, structured according to the IEEE format (4 pages A4, two columns, including a 50 words summary, figures and references). The authors should upload a Microsoft Word file on the conference web site (www.imt.ro/CAS).

The authors should edit the papers, in very good contrast conditions ("Times New Roman" type font, 11pt. size are recommended), on A4 size paper, with 2.5 cm top, left and right margins and 3.5 cm bottom margin. For details, the authors should consult "Guideline for papers" in the INTERNET web page of the conference.

INVITED PAPERS

The invited papers (10 pages A4, two columns, including a 50 words summary, figures and references) will be printed in the format given for the contributed papers. The invited speakers should send the file of the paper by e-mail.

DEADLINES

- June 10th, 2009
Submission of the contributed and invited papers.
- July 15th, 2009
Notification of the final acceptance of contributed papers.

GENERAL INFORMATION

OFFICIAL LANGUAGE: All written materials and oral presentations should be in English.

LOCATION

CAS 2009 will be held from Monday 12th to Wednesday 14th of October in Sinaia - "the Pearl of Carpathian Mountains". Sinaia is a beautiful mountain resort, located at about 125 km (by car or by train) from Bucharest. The weather in Sinaia is mild and sunny in October, the average temperature being about 12^oC.

The participants are offered the opportunity to visit the splendid Swiss-like town, with its famous Peles Castle and the Casino, and also to make trips in the mountains or to the Bran (Dracula's) Castle.

REGISTRATION FORM

Participants must register in advance and reserve accommodation, by sending the Registration Form, by mail or by fax, to the CAS Office.

The Registration Form will be sent, with the final notification, to all the authors, or on request.

The payment formalities for accommodation will be carried out by the participants on their arrival at Sinaia, Romania, at Sinaia Hotel.

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